



## **AO4402**

# **N-Channel Enhancement Mode Field Effect Transistor**

## **General Description**

The AO4402 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications.

### **Features**

 $V_{DS}(V) = 30V$ 

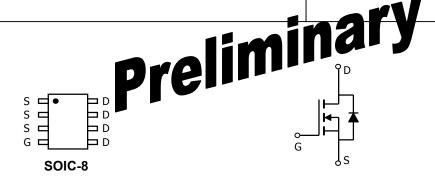
 $I_{D} = 12A$ 

 $R_{DS(ON)}$  < 13m $\Omega$  ( $V_{GS}$  = 10V)

 $R_{DS(ON)}$  < 16m $\Omega$  (V<sub>GS</sub> = 4.5V)

 $R_{DS(ON)}$  < 22m $\Omega$  (V<sub>GS</sub> = 2.5V)

 $R_{DS(ON)}$  < 35m $\Omega$  (V<sub>GS</sub> = 1.8V)



Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		$V_{DS}$	30	V				
Gate-Source Voltage		$V_{GS}$	±12	V				
Continuous Drain	T <sub>A</sub> =25°C		12					
Current <sup>A</sup>	T <sub>A</sub> =70°C	$I_D$	10	Α				
Pulsed Drain Current B		I <sub>DM</sub>	80					
	T <sub>A</sub> =25°C	D	3	W				
Power Dissipation	T <sub>A</sub> =70°C	$-P_{D}$	2.1	VV				
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 150	°C				

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{ heta JA}$	20	40	°C/W			
Maximum Junction-to-Ambient A	Steady-State	Γ∖ <sub>θ</sub> JA	40		°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	10	16	°C/W			

### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V				1	
			T <sub>J</sub> =55°C			5	μΑ
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ = ±12V	•			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}$ = $V_{GS}$ $I_D$ =250μA		0.5	0.75	1.4	V
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =5V		60			Α
,		V <sub>GS</sub> =10V, I <sub>D</sub> =12A			10.8	13	mΩ
			T <sub>J</sub> =125°C		16	19.2	11152
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS}$ =4.5V, $I_D$ =10A			13	16	mΩ
		$V_{GS}$ =2.5V, $I_D$ =8A			18.5	22	mΩ
		$V_{GS}$ =1.8V, $I_D$ =4A		28	35	mΩ	
<b>g</b> FS	Forward Transconductance	$V_{DS}$ =5V, $I_D$ =5A		20	32		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.68	1	V
Is	Maximum Body-Diode Continuous Current					4.5	Α
DYNAMIC	PARAMETERS		·		•	•	
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz			1700		pF
C <sub>oss</sub>	Output Capacitance				194		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				142		pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			0.6		Ω
SWITCHI	NG PARAMETERS						
$Q_g$	Total Gate Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =15V, I <sub>D</sub> =12A			19.4		nC
$Q_{gs}$	Gate Source Charge				3.3		nC
$Q_{gd}$	Gate Drain Charge				6.2		nC
t <sub>D(on)</sub>	Turn-On DelayTime				8		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_{L}$ =1.25 $\Omega$ , $R_{GEN}$ =6 $\Omega$			4		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				52		ns
t <sub>f</sub>	Turn-Off Fall Time				4		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =5A, dI/dt=100A/μs			20		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	e I <sub>F</sub> =5A, dI/dt=100A/μs			16		nC

A: The value of  $R_{\theta,JA}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using  $80\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The SOA curve provides a single pulse rating.